## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application:

N. KATOH et al

Serial No. 10/084,435 Filed: February 28, 2002

Group Art Unit:

2825

Examiner:

P. Kik

For:

SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE, STORAGE MEDIUM ON WHICH CELL LIBRARY IS STORED AND DESIGNING METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Mail Stop Patent Application P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, the Applicants inform the Examiner of the documents cited during prosecution of the parent application, U.S. Serial No. 10/084,435.

The Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the references have been considered.

Respectfully submitted,

Shrinath Malur

Registration No. 34,663

Here W Stockman RN21,021

Attorney of Record

MATTINGLY, STANGER & MALUR 1800 Diagonal Road, Suite 370 Alexandria, Virginia 22314 (703) 684-1120

Date: April 20, 2004

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